

Notice of References Cited	Application/Control No. 10/754,921	Applicant(s)/Patent Under Reexamination WELCH ET AL.	
	Examiner David Turocy	Art Unit 1762	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,140,456	10-2000	Lee et al.	528/196
*	B	US-5,879,808	03-1999	Wary et al.	428/411.1
*	C	US-5,075,174	12-1991	Pyle, Jeffrey	428/447
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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